

Docket No.: 60188-448

PATENT**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of : Customer Number: 20277
: :
Keiichi Fujimoto et al. : Confirmation Number: 2785
: :
Serial No.: 09/964,480 : Group Art Unit: 2829
: :
Filed: September 28, 2001 : Examiner: Paresh Patel
: :
For: SEMICONDUCTOR INTEGRATED CIRCUIT TESTING SYSTEM AND
METHOD

PETITION FOR EXTENSION OF TIME

Mail Stop Extension of Time
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

It is respectfully requested that the time for response to the Office Action dated April 10, 2003, now due to expire July 10, 2003, be extended for three months and set to expire on October 10, 2003.

Please charge the extension fee of \$950.00 to Deposit Account No. 500417. Please charge any additional fees or credit any overpayment to Deposit Account No. 500417.

Respectfully submitted,
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Date: October 10, 2003

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W. S. E. 10/10/03
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